CHARGE ANY DEFICIENCY IN THE USE FOR THIS PAPER TO DESCRIPTION TO

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Akira TERAOKA

Attn: APPLICATION BRANCH

Serial No. NEW

Docket No. 2000 0311A

Filed March 24, 2000

X-RAY INSPECTION METHOD AND APPARATUS USED FOR THE SAME

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents Washington, DC 20231

Sir:

Prior to examination of the above-referenced U.S. patent application please amend the application as follows:

IN THE CLAIMS:

Please amend the claims as follows:

Claim 4, line 1, delete "or 2".

Claim 8, line 1, delete "or 6".

Claim 9, line 1, change "one of claims 5-8" to --Claim 5--.

Claim 10, line-1, change "one of Claims 5-9" to --Claim 5--.

Please add the following new claims:

--12. A method of X-ray inspection according to Claim 2, wherein the straight line to be the central axis and the axis of rotation is set to be vertical to a stage on which the sample is placed.

